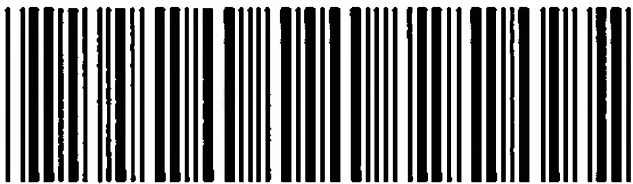


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/646,709	OHNISHI, SADAYUKI	
	Examiner	Art Unit	
	Phat X. Cao	2814	

SEARCHED			
Class	Subclass	Date	Examiner
257	759	5/28/2006	PC
257	762	5/28/2006	PC
257	758	5/28/2006	PC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST: IS&R		